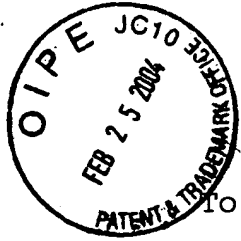


TSMC-00-577C



February 18, 2004

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/755,496 01/12/04

Shao-Yu Chou

ERASE METHOD OF SPLIT GATE FLASH
MEMORY REFERENCE CELLS

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents
P.O. Box 1450, Alexandria, VA 22313-1450, on February 23, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 2/23/04

U.S. Patent 6,122,198 to Haddad et al., "Bit by Bit APDE Verify for Flash Memory Applications," teaches a method for guaranteeing that an erased cell threshold voltage in a two bit per cell Flash EEPROM falls within prescribed limits.

U.S. Patent 5,675,537 to Bill et al., "Erase Method for Page Mode Multiple Bits-Per-Cell Flash EEPROM," teaches a method where overerasure of memory cells in a Flash EPROM is prevented by halting erasure once a prescribed cell threshold is reached.

U.S. Patent 5,801,985 to Roohparvar et al., "Memory System Having Programming Control Parameters," teaches a method where non-volatile memory is used to set memory system parameters such as threshold, word length, and addressing scheme.

U.S. Patent 6,073,204 to Lakhani et al., "Memory System Having Flexible Architecture and Method," teaches a method using a single memory controller connected to several memory devices using common bus architecture to optimize memory performance.

Sincerely,

A handwritten signature in black ink, appearing to read "SBA", followed by a large, stylized circular flourish.

Stephen B. Ackerman,
Reg. No. 37761

(Use several sheets if necessary)

TSMC-00-577C

10/755,496

Shao - Yu Chou

01/12/04

Group Art Unit

A circular ink stamp from the Office of the Patent Examiner. The text "OFFICE OF THE PATENT EXAMINER" is arranged in a circle around the date "FEB 25 2006". The word "PATENT" is at the bottom, and "EXAMINER" is at the top.

FOREIGN PATENT DOCUMENTS											
	DOCUMENT NUMBER					DATE	COUNTRY	CLASS	SUBCLASS	Translation	
										YES	NO

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.